

36th RD50 Workshop (CERN - - online Workshop)

Wednesday 3 June 2020

Detector Characterization, NIEL and Irradiation Facilities: Detector Characterization, NIEL and Irradiation Facilities

(14:00 - 17:00)

time	[id] title	presenter
14:00	[33] Determination of the proton related damage on commercial and high-ohmic silicon pad diodes	NIKOLOPOULOS, Konstantinos
14:20	[21] Fluence profiling at JSI TRIGA reactor irradiation facility	SOLA, Valentina
14:40	[14] Measurement of the charge collection for the irradiated n^+p pad diode in the region of the n^+p interface	HAJHEIDARI, Mohammadtaghi
15:00	[24] Timing resolution on a 3D silicon pixel detector	DE SIMONE, Dario
15:20	Break	
15:40	[26] Investigation on the effects of trapped charge on the signal from subsequent laser pulses in irradiated p-type sensors	DIEHL, Leena
16:00	[39] TPA-TCT -- Two Photon Absorption - Transient Current Technique	WIEHE, Moritz Oliver
16:20	[40] 1550 nm Femtosecond Fiber Laser System for the Two-Photon Excitation of Transient Currents in Semiconductor Detectors	PÉREZ-MILLÁN, P.
16:40	[27] [US] Measurement of the silicon effective band gap energy with the ATLAS pixel detector	GRUMMER, Aidan